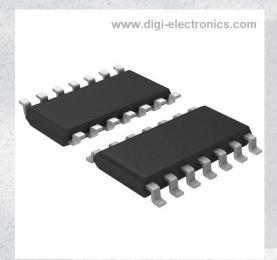


TLV9004QDRQ1 Datasheet



https://www.DiGi-Electronics.com

DiGi Electronics Part Number TLV9004QDRQ1-DG

Manufacturer Texas Instruments

Manufacturer Product Number TLV9004QDRQ1

Description IC OPAMP GP 4 CIRCUIT 14SOIC

Detailed Description General Purpose Amplifier 4 Circuit Rail-to-Rail 14-

SOIC



Tel: +00 852-30501935

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Purchase and inquiry

Manufacturer Product Number:	Manufacturer:
TLV9004QDRQ1	Texas Instruments
Series:	Product Status:
	Active
Amplifier Type:	Number of Circuits:
General Purpose	4
Output Type:	Slew Rate:
Rail-to-Rail	2V/μs
Gain Bandwidth Product:	Current - Input Bias:
1 MHz	5 pA
Voltage - Input Offset:	Current - Supply:
400 μV	60µA (x4 Channels)
Current - Output / Channel:	Voltage - Supply Span (Min):
40 mA	1.8 V
Voltage - Supply Span (Max):	Operating Temperature:
5.5 V	-40°C ~ 125°C (TA)
Grade:	Qualification:
Automotive	AEC-Q100
Mounting Type:	Package / Case:
Surface Mount	14-SOIC (0.154", 3.90mm Width)
Supplier Device Package:	Base Product Number:
14-SOIC	TLV9004

Environmental & Export classification

8542.33.0001

RoHS Status:	Moisture Sensitivity Level (MSL):
ROHS3 Compliant	2 (1 Year)
REACH Status:	ECCN:
REACH Unaffected	EAR99
HTSUS:	

TLV900x-Q1 Low-Power RRIO 1-MHz Automotive Operational Amplifier

1 Features

AEC-Q100 qualified for automotive applications

Temperature grade 1: –40°C to +125°C, T_△

- Device HBM ESD classification level 2

Device CDM ESD classification level C6

Scalable CMOS amplifier for low-cost applications

Rail-to-rail input and output

Low input offset voltage: ±0.4 mV

Unity-gain bandwidth: 1 MHz

Low broadband noise: 27 nV/√ Hz

Low input bias current: 5 pA

Low quiescent current: 60 µAVCh

Unity-gain stable

Internal RFI and EMI filter

Operational at supply voltages as low as 1.8 V

Easier to stabilize with higher capacitive load due to resistive open-loop output impedance

Functional Safety-Capable

Functional Safety Information

2 Applications

- Optimized for AEC-Q100 grade 1 applications
- Infotainment and Cluster
- Passive safety
- Body electronics and lighting
- HEV/EV inverter and motor control
- On-board (OBC) and wireless charger
- Power-train current sensor
- Advanced driver assistance systems (ADAS)
- Single-supply, low-side, unidirectional currentsensing circuit

3 Description

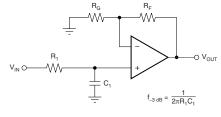
The TLV900x-Q1 family includes single (TLV9001-(TLV9002-Q1), and quad-channel dual (TLV9004-Q1) low-voltage (1.8 V to 5.5 V) operational amplifiers (op amps) with rail-to-rail input and output swing capabilities. These op amps provide a costeffective solution for space-constrained automotive applications such as infotainment and lighting where low-voltage operation and high capacitive-load drive are required. The capacitive-load drive of the TLV900x-Q1 family is 500 pF, and the resistive openloop output impedance makes stabilization easier with much higher capacitive loads. These op amps are designed specifically for low-voltage operation (1.8 V to 5.5 V) with performance specifications similar to the TLV600x-Q1 devices.

The robust design of the TLV900x-Q1 family simplifies circuit design. The op amps feature unity-gain stability, an integrated RFI and EMI rejection filter, and no-phase reversal in overdrive conditions.

Package Information(3)

. •	. achage information				
PART NUMBER (1)	PACKAGE	BODY SIZE (NOM)			
TLV9001-Q1	DBV (SOT-23, 5)	1.60 mm × 2.90 mm			
1LV9001-Q1	DCK (SC70, 5)	1.25 mm × 2.00 mm			
	D (SOIC, 8)	3.91 mm × 4.90 mm			
TLV9002-Q1	PW (TSSOP, 8)(2)	3.00 mm × 4.40 mm			
	DGK (VSSOP, 8)	3.00 mm × 3.00 mm			
	DYY (SOT-23, 14)	4.20 mm × 1.90 mm			
TLV9004-Q1	D (SOIC, 14)	8.65 mm × 3.91 mm			
	PW (TSSOP, 14)	4.40 mm × 5.00 mm			

- (1) For all available packages, see the orderable addendum at the end of the data sheet.
- Package is for preview only.
- See Device Comparison Table (3)



 $\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_C}\right) \left(\frac{1}{1 + sR_cC_A}\right)$

Single-Pole, Low-Pass Filter



Table of Contents

1 Features	8.2 Functional Block Diagram	10
2 Applications 1	-	
3 Description	·	
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4 Revision History NOTE: Page numbers for previous revisions may differ		D
Changes from Revision D (November 2022) to Revi		Page
Changed the status of the DBV package from: prev	riew to: active	1
Changes from Revision C (October 2021) to Revision	on D (December 2022)	Page
Deleted preview tag for SC70 (5) from Device inform	mation section	1
Changed formatting of Pin Configuration and Function		
Added Thermal Information for Single Channel DCk		
Changes from Revision B (March 2021) to Revision	C (October 2021)	Page
Deleted preview tag for SOT-23 (14) and TSSOP (1)		
Added preview tags for TLV9001-Q1 SOT-23 (5) an		
Added TLV9001-Q1 GPN to the data sheet		
Added TLV9001-Q1 to Device Comparison Table se		
Added TLV9001-Q1 DBV (SOT-23) and DCK (SC70)		
Changes from Revision A (June 2020) to Revision I	B (March 2021)	Page
 Changed the numbering format for tables, figures a 	· · · · · · · · · · · · · · · · · · ·	
 Added Functional Safety-Capable document link in 		
 Deleted preview tag for VSSOP (8) from Device info 		
 Added note 4 to differential input voltage in Absolute 		
Added Thermal Information for DGK package Added Thermal Information for DVV package		
Added Thermal Information for DYY package		9 ——
Changes from Revision * (May 2019) to Revision A		Page
Changed the device status from Advance Information		
• Added end equipment links in Application section		
• Deleted preview tag for SOIC (8) from Device inform		
• Added SOT-23 (14) in Device Information section		
• Deleted preview tag for SOIC (14) from Device info	rmation section	1



TLV9001-Q1, TLV9002-Q1, TLV9004-Q1 SBOS980E – MAY 2019 – REVISED APRIL 2023



5 Device Comparison Table

DEVICE	NO. OF	PACKAGE LEAD				DS	
	CHANNELS	SOT-23 DBV	SC70 DCK	SOIC D	TSSOP PW	VSSOP DGK	SOT-23 DYY
TLV9001-Q1	1	5	5	_	_	_	
TLV9002-Q1	2	_	_	8	8	8	_
TLV9004-Q1	4	_	_	14	14	_	14

6 Pin Configuration and Functions

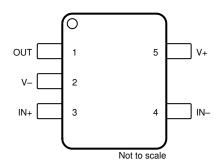


Figure 6-1. TLV9001-Q1 DBV Package, 5-Pin SOT-23 (Top View)

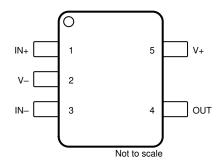


Figure 6-2. TLV9001-Q1 DCK Package, 5-Pin SC70 (Top View)

Table 6-1. Pin Functions: TLV9001-Q1

	PIN		TYPE(1)	DESCRIPTION	
NAME	SOT-23	SC70	IIFE		
IN-	4	3	I	Inverting input	
IN+	3	1	I	Noninverting input	
OUT	1	4	0	Output	
V-	2	2	l or —	Negative (low) supply or ground (for single-supply operation)	
V+	5	5	I	Positive (high) supply	

(1) I = input, O = output



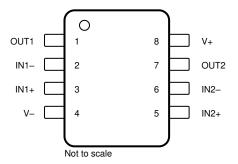


Figure 6-3. TLV9002-Q1 D, DGK, PW Packages, 8-Pin SOIC, VSSOP, TSSOP (Top View)

Table 6-2. Pin Functions: TLV9002-Q1

P	IN	TYPE(1)	DESCRIPTION	
NAME	NO.		DESCRIPTION	
IN1-	2	I	Inverting input, channel 1	
IN1+	3	I	Noninverting input, channel 1	
IN2-	6	I	Inverting input, channel 2	
IN2+	5	I	Noninverting input, channel 2	
OUT1	1	0	Output, channel 1	
OUT2	7	0	Output, channel 2	
V-	4	I or —	Negative (low) supply or ground (for single-supply operation)	
V+	8	I	Positive (high) supply	

(1) I = input, O = output



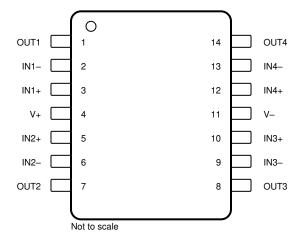


Figure 6-4. TLV9004-Q1 D, PW, DYY Packages, 14-Pin SOIC, TSSOP, SOT-23 (Top View)

Table 6-3. Pin Functions: TLV9004-Q1

P	PIN	TYPE ⁽¹⁾	DESCRIPTION	
NAME	NO.	ITPE	DESCRIPTION	
IN1-	2	ı	Inverting input, channel 1	
IN1+	3	I	Noninverting input, channel 1	
IN2-	6	I	Inverting input, channel 2	
IN2+	5	I	Noninverting input, channel 2	
IN3-	9	I	Inverting input, channel 3	
IN3+	10	ı	Noninverting input, channel 3	
IN4-	13	I	Inverting input, channel 4	
IN4+	12	I	Noninverting input, channel 4	
NC	_	_	No internal connection	
OUT1	1	0	Output, channel 1	
OUT2	7	0	Output, channel 2	
OUT3	8	0	Output, channel 3	
OUT4	14	0	Output, channel 4	
V-	11	I or —	Negative (low) supply or ground (for single-supply operation)	
V+	4	I	Positive (high) supply	

(1) I = input, O = output



7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
Supply voltage ([V+] – [V	<u>])</u>		0	6	V
	Voltage ⁽²⁾	Common-mode	(V-) - 0.5	(V+) + 0.5	V
Signal input pins	voilage(=/	Differential (4)		(V+) - (V-) + 0.2	V
	Current ⁽²⁾	·	-10	10	mA
Output short-circuit ⁽³⁾		Continuous	3	mA	
Operating, T _A			-55	150	°C
Junction, T _J			150	°C	
Storage, T _{stg}			-65	150	°C

- (1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Input pins are diode-clamped to the power-supply rails. Input signals that may swing more than 0.5 V beyond the supply rails must be current limited to 10 mA or less.
- (3) Short-circuit to ground, one amplifier per package.
- (4) Differential input voltages greater than 0.5 V applied continuously can result in a shift to the input offset voltage and quiescent current above the maximum specifications of these parameters. The magnitude of this effect increases as the ambient operating temperature rises.

7.2 ESD Ratings

			VALUE	UNIT
	Electrostatic discharge	Human-body model (HBM), per AEC Q100-002 ⁽¹⁾	±2000	V
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	±1000	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with ANSI/ESDA/JEDEC JS-001 Specification.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
Vs	Supply voltage	1.8	5.5	V
T _A	Specified temperature	-40	125	°C

7.4 Thermal Information for Single Channel

		TLV9	TLV9001-Q1		
	THERMAL METRIC (1)	DBV ⁽²⁾ (SOT-23)	DCK (SC70)	UNIT	
		5 PINS	5 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	232.5	239.6	°C/W	
R _{0JC(top)}	Junction-to-case (top) thermal resistance	131.0	148.5	°C/W	
$R_{\theta JB}$	Junction-to-board thermal resistance	99.6	82.3	°C/W	
ΨЈТ	Junction-to-top characterization parameter	66.5	54.5	°C/W	
ΨЈВ	Junction-to-board characterization parameter	99.1	81.8	°C/W	
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	TBD	°C/W	

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

(2) This package option is preview for TLV9001-Q1.

TLV9001-Q1, TLV9002-Q1, TLV9004-Q1

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7.5 Thermal Information for Dual Channel

	THERMAL METRIC (1)	D (SOIC)	DGK (VSSOP)	PW (TSSOP)	UNIT
		8 PINS	8 PINS	8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	151.9	196.6	TBD	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	92.0	86.2	TBD	°C/W
R _{0JB}	Junction-to-board thermal resistance	95.4	118.3	TBD	°C/W
ΨЈТ	Junction-to-top characterization parameter	40.2	23.2	TBD	°C/W
ΨЈВ	Junction-to-board characterization parameter	94.7	116.7	TBD	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and ICPackage Thermal Metrics application report.

7.6 Thermal Information for Quad Channel

	THERMAL METRIC (1)	D (SOIC)	DYY (SOT-23)	SOT-23) PW (TSSOP)		
		14 PINS	14 PINS	14 PINS		
R _{0JA}	Junction-to-ambient thermal resistance	115.1	154.3	135.3	°C/W	
R _{0JC(top)}	Junction-to-case (top) thermal resistance	71.2	86.8	63.5	°C/W	
R _{θJB}	Junction-to-board thermal resistance	71.1	67.9	78.4	°C/W	
ΨЈТ	Junction-to-top characterization parameter	29.6	10.1	13.6	°C/W	
ΨЈВ	Junction-to-board characterization parameter	70.7	67.5	77.9	°C/W	

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and ICPackage Thermal Metrics application report.



7.7 Electrical Characteristics

For $V_S = (V+) - (V-) = 1.8 \text{ V}$ to 5.5 V (±0.9 V to ±2.75 V), $T_A = 25 \,^{\circ}\text{C}$, $R_L = 10 \,\text{k}\Omega$ connected to $V_S / 2$, and $V_{CM} = V_{OUT} = V_S / 2$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFFSET	VOLTAGE					
V _{OS}	Input offset voltage	Vs = 5 V		±0.4	±1.85	mV
V OS	imput oliset voltage	$Vs = 5 V$, $T_A = -40^{\circ}C$ to 125°C			±2	mV
dV _{OS} /dT	V _{OS} vs temperature	$T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$		±0.6		μV/°C
PSRR	Power-supply rejection ratio	V _S = 1.8 to 5.5 V, V _{CM} = (V–)	80	105		dB
INPUT VC	DLTAGE RANGE					
V _{CM}	Common-mode voltage range	No phase reversal, rail-to-rail input	(V-) - 0.1		(V+) + 0.1	V
		$V_S = 1.8 \text{ V}, (V-) - 0.1 \text{ V} < V_{CM} < (V+) - 1.4 \text{ V},$ $T_A = -40^{\circ}\text{C}$ to 125°C		86	, ,	dB
		V _S = 5.5 V, (V-) - 0.1 V < V _{CM} < (V+) - 1.4 V, T _A = -40°C to 125°C		95		dB
CMRR	Common-mode rejection ratio	$V_S = 5.5 \text{ V}, (V-) - 0.1 \text{ V} < V_{CM} < (V+) + 0.1 \text{ V},$ $T_A = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$	63	77		dB
		V _S = 1.8 V, (V-) - 0.1 V < V _{CM} < (V+)+ 0.1 V, T _A = -40°C to 125°C			dB	
INPUT BI	AS CURRENT					
I _B	Input bias current	Vs = 5 V		±5		pА
I _{os}	Input offset current			±2		pА
NOISE						
En	Input voltage noise (peak-to-peak)	f = 0.1 Hz to 10 Hz, Vs = 5 V		4.7		μV_{PF}
_	I to to to to to	f = 1 kHz, Vs = 5 V		30		nV/√F
e _n	Input voltage noise density	f = 10 kHz, Vs = 5 V		27		nV/√H
i _n	Input current noise density	f = 1 kHz, Vs = 5 V		23		fA/√H
INPUT CA	APACITANCE			,	1	
C _{ID}	Differential			1.5		pF
C _{IC}	Common-mode			5		pF
OPEN-LO	OOP GAIN					
OPEN-LOOP GAIN		V_S = 5.5 V, (V-) + 0.05 V < V_O < (V+) - 0.05 V, R_L = 10 k Ω	104	117		dB
Λ	Open leen veltage gein	$V_S = 1.8 \text{ V}, (V-) + 0.04 \text{ V} < V_O < (V+) - 0.04 \text{ V},$ $R_L = 10 \text{ k}\Omega$		100		dB
A _{OL}	Differential	$V_S = 1.8 \text{ V}, (V-) + 0.1 \text{ V} < V_O < (V+) - 0.1 \text{ V},$ $R_L = 2 \text{ k}\Omega$		115		dB
		$V_S = 5.5 \text{ V}, (V-) + 0.15 \text{ V} < V_O < (V+) - 0.15 \text{ V},$ $R_L = 2 \text{ k}\Omega$		130		dB
FREQUE	NCY RESPONSE					
GBW	Gain-bandwidth product	Vs = 5 V		1		MHz
φ _m	Phase margin	V _S = 5.5 V, G = 1		78		degree
SR	Slew rate	Vs = 5 V		2		V/µs
to	Settling time	To 0.1%, $V_S = 5 \text{ V}$, 2 V Step , $G = +1$, $C_L = 100 \text{ pF}$		2.5		μs
t _S	Journal of the	To 0.01%, $V_S = 5 \text{ V}$, 2 V Step , $G = +1$, $C_L = 100 \text{ pF}$		3		μs
t _{OR}	Overload recovery time	$V_S = 5 \text{ V}, V_{IN} \times \text{gain} > V_S$		0.85		μs
THD+N	Total harmonic distortion + noise	V_S = 5.5 V, V_{CM} = 2.5 V, V_O = 1 V_{RMS} , G = +1, f = 1 kHz, 80 kHz measurement BW		0.004		%
	·		-		1	
OUTPUT				10	20	mV
	V-14	$V_S = 5.5 \text{ V}, R_L = 10 \text{ k}\Omega$		10	- 1	
	Voltage output swing from supply rails	$\begin{aligned} &V_{S}=5.5 \text{ V, } R_{L}=10 \text{ k}\Omega \\ &V_{S}=5.5 \text{ V, } R_{L}=2 \text{ k}\Omega \end{aligned}$		35	55	mV
OUTPUT V _O	Voltage output swing from supply rails Short-circuit current					mV mA



TLV9001-Q1, TLV9002-Q1, TLV9004-Q1

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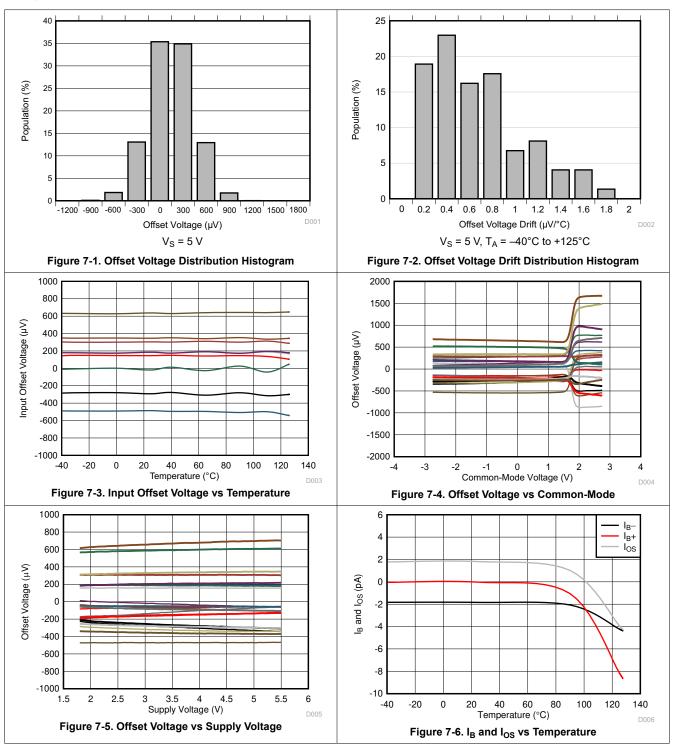
7.7 Electrical Characteristics (continued)

For V_S = (V+) – (V–) = 1.8 V to 5.5 V (±0.9 V to ±2.75 V), T_A = 25 °C, R_L = 10 k Ω connected to V_S / 2, and V_{CM} = V_{OUT} = V_S / 2 (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vs	Specified voltage range		1.8 (±0.9)		5.5 (±2.75)	V
1-	Quiescent current per amplifier	I _O = 0 mA, V _S = 5.5 V		60	80	μA
'Q	T _Q Quiescent current per ampliller	$I_O = 0$ mA, $V_S = 5.5$ V, $T_A = -40$ °C to 125°C			85	μA
	Power-on time	V _S = 0 V to 5 V, to 90% I _Q level		50		μs

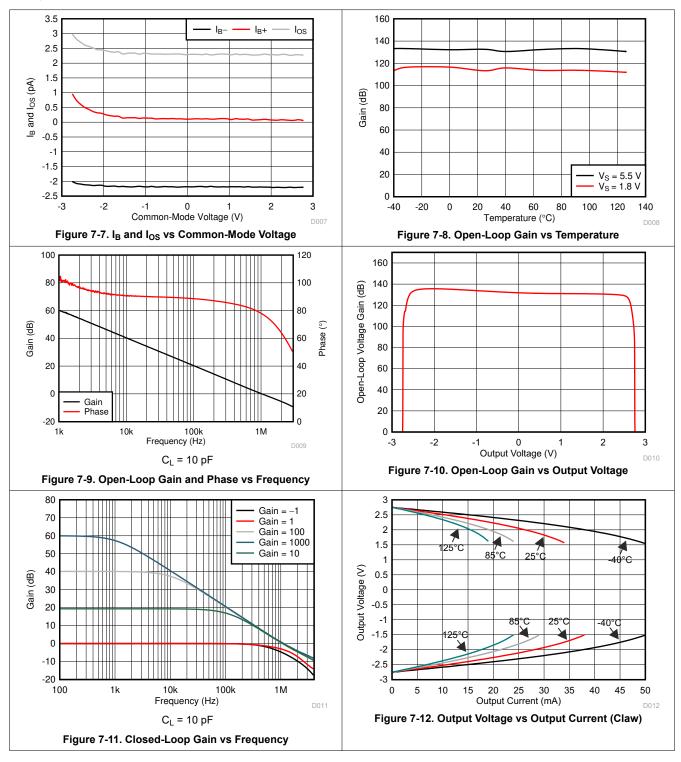


7.8 Typical Characteristics



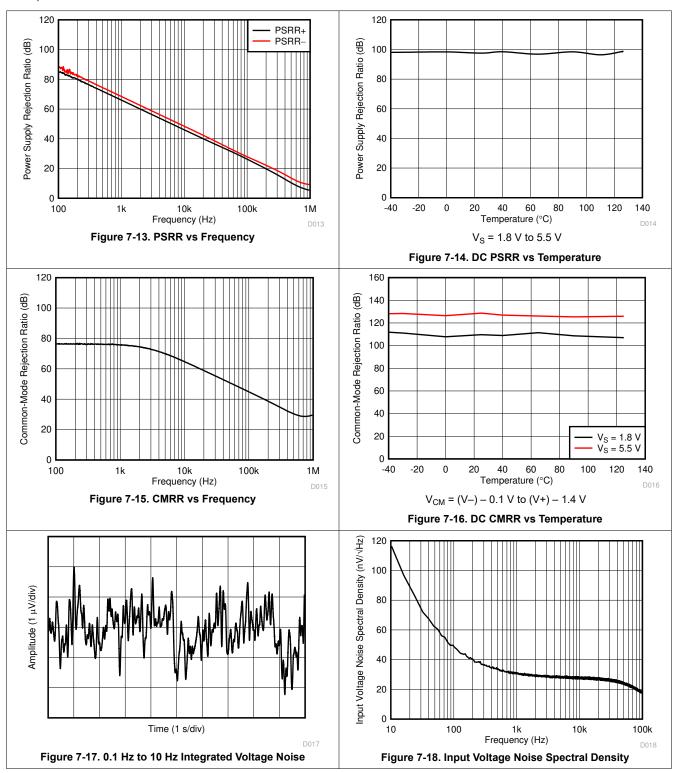
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7.8 Typical Characteristics (continued)



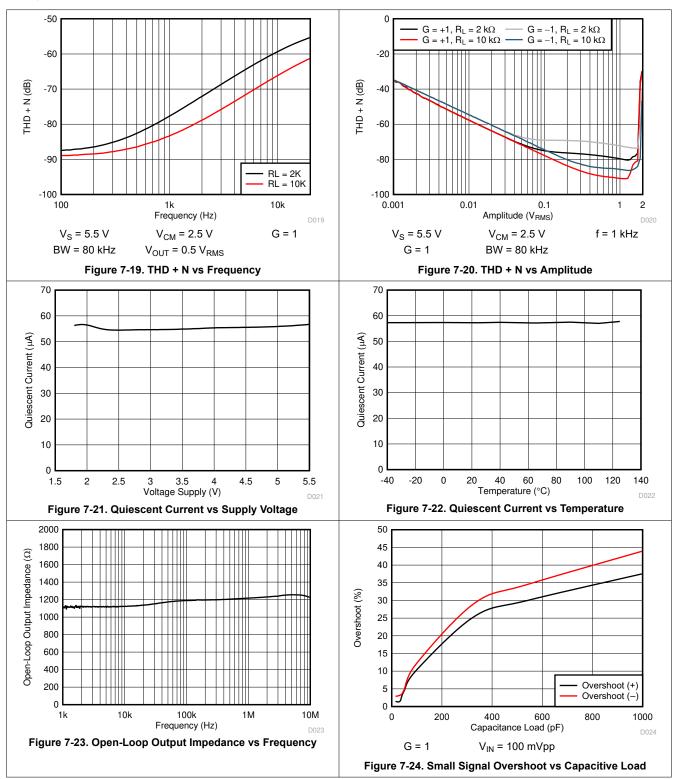


7.8 Typical Characteristics (continued)



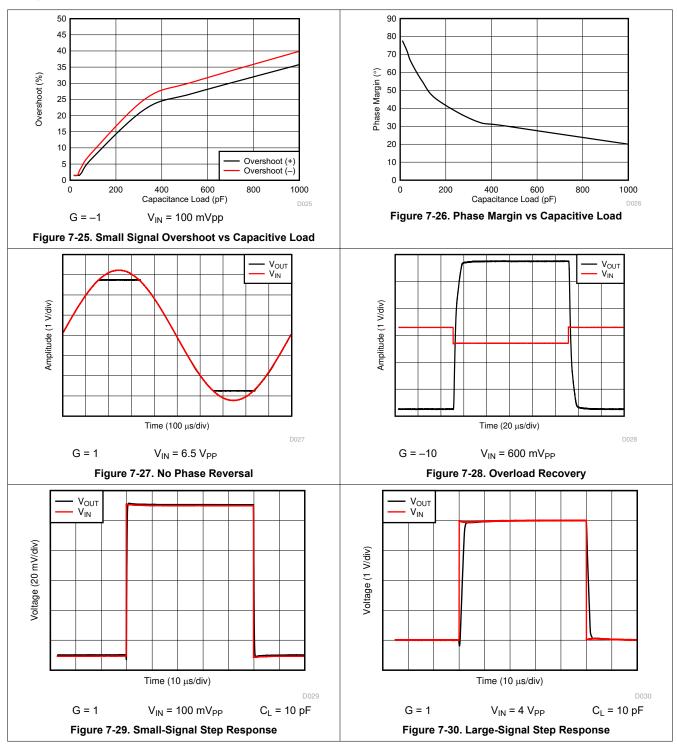
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7.8 Typical Characteristics (continued)



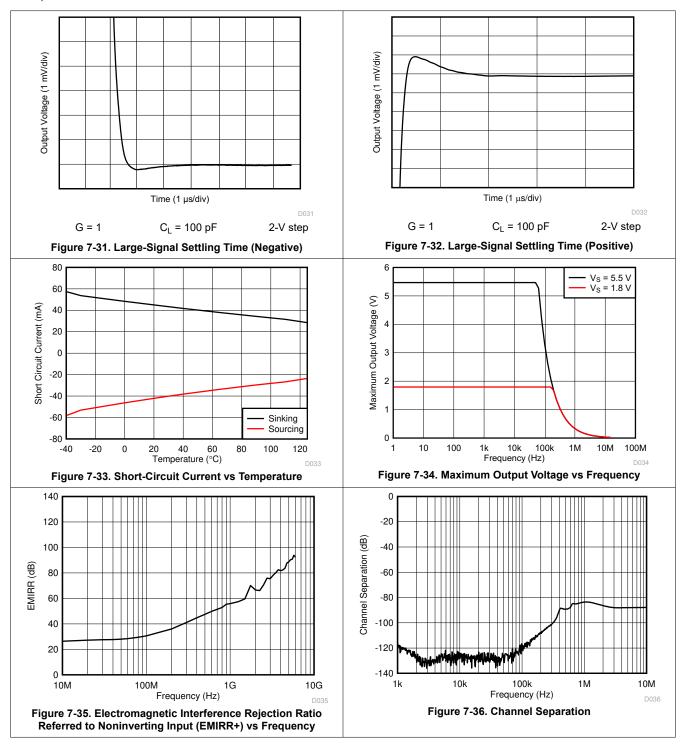


7.8 Typical Characteristics (continued)



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7.8 Typical Characteristics (continued)



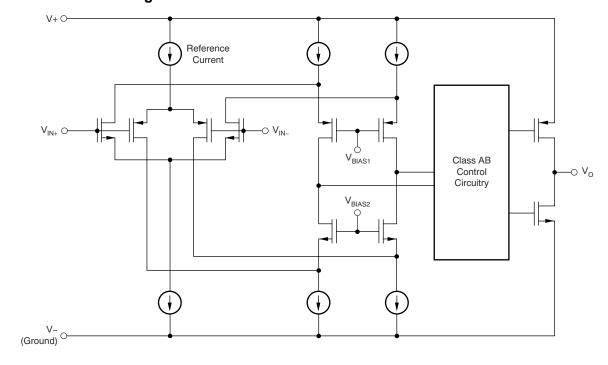


8 Detailed Description

8.1 Overview

The TLV900x-Q1 is a family of automotive qualified, low-power, rail-to-rail input and output op amps. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and are designed for a wide range of general-purpose applications. The input common-mode voltage range includes both rails and allows the TLV900x-Q1 family to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes them suitable for driving sampling analog-to-digital converters (ADCs).

8.2 Functional Block Diagram



TLV9001-Q1, TLV9002-Q1, TLV9004-Q1

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8.3 Feature Description

8.3.1 Operating Voltage

The TLV900x-Q1 family of op amps are for operation from 1.8 V to 5.5 V. In addition, many specifications such as input offset voltage, quiescent current, offset current, and short circuit current apply from -40°C to 125°C. Parameters that vary significantly with operating voltages or temperature are shown in the typical characteristics section.

8.3.2 Rail-to-Rail Input

The input common-mode voltage range of the TLV900x-Q1 family extends 100 mV beyond the supply rails for the full supply voltage range of 1.8 V to 5.5 V. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair, as shown in the *Functional Block Diagram* section. The N-channel pair is active for input voltages close to the positive rail, typically (V+) - 1.4 V to 100 mV above the positive supply, whereas the P-channel pair is active for inputs from 100 mV below the negative supply to approximately (V+) - 1.4 V. There is a small transition region, typically (V+) - 1.2 V to (V+) - 1 V, in which both pairs are on. This 100-mV transition region can vary up to 100 mV with process variation. Thus, the transition region (with both stages on) can range from (V+) - 1.4 V to (V+) - 1.2 V on the low end, and up to (V+) - 1 V to (V+) - 0.8 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD can degrade compared to device operation outside this region.

8.3.3 Rail-to-Rail Output

Designed as a low-power, low-voltage operational amplifier, the TLV900x-Q1 family delivers a robust output drive capability. A class-AB output stage with common-source transistors achieves full rail-to-rail output swing capability. For resistive loads of 10 k Ω , the output swings to within 20 mV of either supply rail, regardless of the applied power-supply voltage. Different load conditions change the ability of the amplifier to swing close to the rails.

8.3.4 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from a saturated state to a linear state. The output devices of the operational amplifier enter a saturation region when the output voltage exceeds the rated operating voltage, because of the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return to the linear state. After the charge carriers return to the linear state, the device begins to slew at the specified slew rate. Therefore, the propagation delay (in case of an overload condition) is the sum of the overload recovery time and the slew time. The overload recovery time for the TLV900x-Q1 family is approximately 850 ns.

8.4 Device Functional Modes

The TLV900x-Q1 family has a single functional mode. The devices are powered on as long as the power-supply voltage is between 1.8 V (\pm 0.9 V) and 5.5 V (\pm 2.75 V).

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

The TLV900x-Q1 family of low-power, rail-to-rail input and output operational amplifiers is specifically designed for portable applications. The devices operate from 1.8 V to 5.5 V, are unity-gain stable, and are suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving less than or equal to $10-k\Omega$ loads connected to any point between V+ and V-. The input common-mode voltage range includes both rails, and allows the TLV900x-Q1 devices to be used in any single-supply application.

9.2 Typical Application

9.2.1 TLV900x-Q1 Low-Side, Current Sensing Application

Figure 9-1 shows the TLV900x-Q1 configured in a low-side current sensing application.

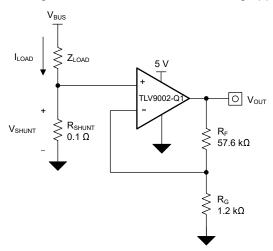


Figure 9-1. TLV900x-Q1 in a Low-Side, Current-Sensing Application



9.2.1.1 Design Requirements

The design requirements for this design are:

Load current: 0 A to 1 AOutput voltage: 4.9 V

Maximum shunt voltage: 100 mV

9.2.1.2 Detailed Design Procedure

The transfer function of the circuit in Figure 9-1 is given in Equation 1:

$$V_{OUT} = I_{LOAD} \times R_{SHIINT} \times Gain$$
 (1)

The load current (I_{LOAD}) produces a voltage drop across the shunt resistor (R_{SHUNT}). The load current is set from 0 A to 1 A. To keep the shunt voltage below 100 mV at maximum load current, the largest shunt resistor is shown using Equation 2:

$$R_{SHUNT} = \frac{V_{SHUNT_MAX}}{I_{LOAD_MAX}} = \frac{100 \, mV}{1 \, A} = 100 \, m\Omega \tag{2}$$

Using Equation 2, R_{SHUNT} is calculated to be 100 m Ω . The voltage drop produced by I_{LOAD} and R_{SHUNT} is amplified by the TLV900x-Q1 to produce an output voltage of approximately 0 V to 4.9 V. The gain needed by the TLV900x-Q1 to produce the necessary output voltage is calculated using Equation 3:

$$Gain = \frac{(V_{OUT_MAX} - V_{OUT_MIN})}{(V_{IN\ MAX} - V_{IN\ MIN})}$$
(3)

Using Equation 3, the required gain is calculated to be 49 V/V, which is set with resistors R_F and R_G . Equation 4 sizes the resistors R_F and R_G , to set the gain of the TLV900x-Q1 to 49 V/V.

$$Gain = 1 + \frac{(R_F)}{(R_C)} \tag{4}$$

Selecting R_F as 57.6 k Ω and R_G as 1.2 k Ω provides a combination that equals 49 V/V. Figure 9-2 shows the measured transfer function of the circuit shown in Figure 9-1. Notice that the gain is only a function of the feedback and gain resistors. This gain is adjusted by varying the ratio of the resistors and the actual resistors values are determined by the impedance levels that the designer wants to establish. The impedance level determines the current drain, the effect that stray capacitance has, and a few other behaviors. There is no optimal impedance selection that works for every system, choose an impedance that is ideal for the system parameters.

9.2.1.3 Application Curve

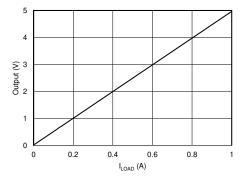


Figure 9-2. Low-Side, Current-Sense Transfer Function



9.2.2 Single-Supply Photodiode Amplifier

Photodiodes are used in many applications to convert light signals to electrical signals. The current through the photodiode is proportional to the photon energy absorbed, and is commonly in the range of a few hundred picoamps to a few tens of microamps. An amplifier in a transimpedance configuration is typically used to convert the low-level photodiode current to a voltage signal for processing in an MCU. The circuit shown in Figure 9-3 is an example of a single-supply photodiode amplifier circuit using the TLV9002-Q1.

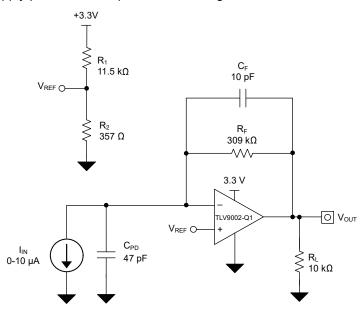


Figure 9-3. Single-Supply Photodiode Amplifier Circuit



9.2.2.1 Design Requirements

The design requirements for this design are:

Supply voltage: 3.3 V
Input: 0 μA to 10 μA
Output: 0.1 V to 3.2 V
Bandwidth: 50 kHz

9.2.2.2 Detailed Design Procedure

The transfer function between the output voltage (V_{OUT}), the input current, (I_{IN}) and the reference voltage (V_{REF}) is defined in Equation 5.

$$V_{OUT} = I_{IN} \times R_F + V_{REF} \tag{5}$$

Where:

$$V_{REF} = V_{+} \times \left(\frac{R_1 \times R_2}{R_1 + R_2}\right) \tag{6}$$

Set V_{REF} to 100 mV to meet the minimum output voltage level by setting R1 and R2 to meet the required ratio calculated in Equation 7.

$$\frac{V_{REF}}{V_{\perp}} = \frac{0.1 \, V}{3.3 \, V} = 0.0303 \tag{7}$$

The closest resistor ratio to meet this ratio sets R1 to 11.5 k Ω and R2 to 357 Ω .

The required feedback resistance can be calculated based on the input current and desired output voltage.

$$R_F = \frac{V_{OUT} - V_{REF}}{I_{IN}} = \frac{3.2 V - 0.1 V}{10 \,\mu A} = 310 \,\frac{kV}{A} \approx 309 \,k\Omega$$
 (8)

Calculate the value for the feedback capacitor based on R_F and the desired –3-dB bandwidth, ($f_{-3 \text{ dB}}$) using Equation 9.

$$C_F = \frac{1}{2 \times \pi \times R_F \times f_{-3 dR}} = \frac{1}{2 \times \pi \times 309 \, k\Omega \times 50 \, kHz} = 10.3 \, pF \approx 10 \, pF$$
 (9)

The minimum op amp bandwidth required for this application is based on the value of R_F , C_F , and the capacitance on the INx– pin of the TLV9002-Q1 which is equal to the sum of the photodiode shunt capacitance, (CPD) the common-mode input capacitance, (CCM) and the differential input capacitance (CD) as Equation 10 shows.

$$C_{IN} = C_{PD} + C_{CM} + C_D = 47 \, pF + 5 \, pF + 1 \, pF = 53 \, pF$$
 (10)

The minimum op amp bandwidth is calculated in Equation 11.

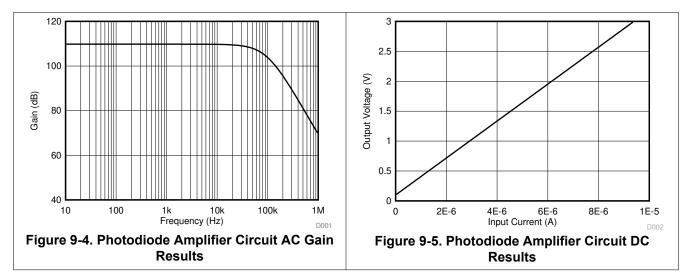
$$f = BGW \ge \frac{c_{IN} + c_F}{2 \times \pi \times R_F \times c_F^2} \ge 324 \, kHz \tag{11}$$

The 1-MHz bandwidth of the TLV900x-Q1 meets the minimum bandwidth requirement and remains stable in this application configuration.



9.2.2.3 Application Curves

The measured current-to-voltage transfer function for the photodiode amplifier circuit is shown in Figure 9-4. The measured performance of the photodiode amplifier circuit is shown in Figure 9-5.



9.3 Power Supply Recommendations

The TLV900x-Q1 family is specified for operation from 1.8 V to 5.5 V (±0.9 V to ±2.75 V); many specifications apply from –40°C to 125°C. The *Typical Characteristics* section presents parameters that may exhibit significant variance with regard to operating voltage or temperature.

CAUTION

Supply voltages larger than 6 V may permanently damage the device; see the *Absolute Maximum Ratings* table.

Place 0.1-µF bypass capacitors close to the power-supply pins to reduce coupling errors from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see the *Layout Guidelines* section.

9.3.1 Input and ESD Protection

The TLV900x-Q1 family incorporates internal ESD protection circuits on all pins. For input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA. Figure 9-6 shows how a series input resistor can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and the value must be kept to a minimum in noise-sensitive applications.

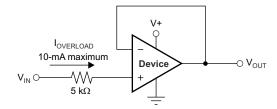


Figure 9-6. Input Current Protection



9.4 Layout

9.4.1 Layout Guidelines

For best operational performance of the device, use good printed circuit board (PCB) layout practices, including:

- Noise can propagate into analog circuitry through the power connections of the board and propagate to the
 power pins of the op amp itself. Bypass capacitors are used to reduce the coupled noise by providing a
 low-impedance path to ground.
 - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as
 close to the device as possible. A single bypass capacitor from V+ to ground is adequate for single-supply
 applications.
- Separate grounding for analog and digital portions of circuitry is one of the simplest and most effective
 methods of noise suppression. One or more layers on multilayer PCBs are usually devoted to ground planes.
 A ground plane helps distribute heat and reduces electromagnetic interference (EMI) noise pickup. Take care
 to physically separate digital and analog grounds, paying attention to the flow of the ground current. For more
 detailed information, see Circuit Board Layout Techniques.
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible.
 If these traces cannot be kept separate, crossing the sensitive trace at a 90 degree angle is much better as opposed to running the traces in parallel with the noisy trace.
- Place the external components as close to the device as possible, as shown in Figure 9-8. Keeping R_F and R_G close to the inverting input minimizes parasitic capacitance.
- Keep the length of input traces as short as possible. Remember that the input traces are the most sensitive
 part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring may significantly reduce leakage currents from nearby traces that are at different potentials.
- Cleaning the PCB following board assembly is recommended for best performance.
- Any precision integrated circuit can experience performance shifts resulting from moisture ingress into the
 plastic package. Following any aqueous PCB cleaning process, baking the PCB assembly is recommended
 to remove moisture introduced into the device packaging during the cleaning process. A low-temperature,
 post-cleaning bake at 85°C for 30 minutes is sufficient for most circumstances.

9.4.2 Layout Example

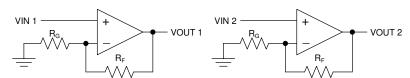


Figure 9-7. Schematic Representation for Figure 11-2

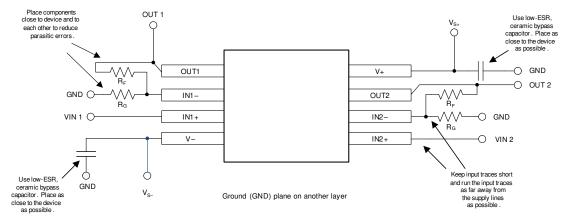


Figure 9-8. Layout Example



10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

For related documentation, see the following:

Texas Instruments, EMI Rejection Ratio of Operational Amplifiers

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGE OPTION ADDENDUM

17-Jun-2023 www.ti.com

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLV9001QDBVRQ1	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	(6) SN	Level-1-260C-UNLIM	-40 to 125	2T5H	Samples
TLV9001QDCKRQ1	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	1MZ	Samples
TLV9002QDGKRQ1	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	27DT	Samples
TLV9002QDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	T9002Q	Samples
TLV9004QDRQ1	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	LV9004Q	Samples
TLV9004QDYYRQ1	ACTIVE	SOT-23-THIN	DYY	14	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	TLV9004Q	Samples
TLV9004QPWRQ1	ACTIVE	TSSOP	PW	14	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	T9004Q	Samples

(1) The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

TLV9004QDRQ1 Texas Instruments IC OPAMP GP 4 CIRCUIT 14SOIC

PACKAGE OPTION ADDENDUM



www.ti.com 17-Jun-2023

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TLV9001-Q1, TLV9002-Q1, TLV9004-Q1:

Catalog: TLV9001, TLV9002, TLV9004

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product



PACKAGE MATERIALS INFORMATION

www.ti.com 5-Nov-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV9001QDBVRQ1	SOT-23	DBV	5	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TLV9001QDCKRQ1	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TLV9002QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.25	3.35	1.25	8.0	12.0	Q1
TLV9002QDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLV9004QDRQ1	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
TLV9004QDYYRQ1	SOT-23- THIN	DYY	14	3000	330.0	12.4	4.8	3.6	1.6	8.0	12.0	Q3
TLV9004QPWRQ1	TSSOP	PW	14	3000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



PACKAGE MATERIALS INFORMATION

www.ti.com 5-Nov-2024



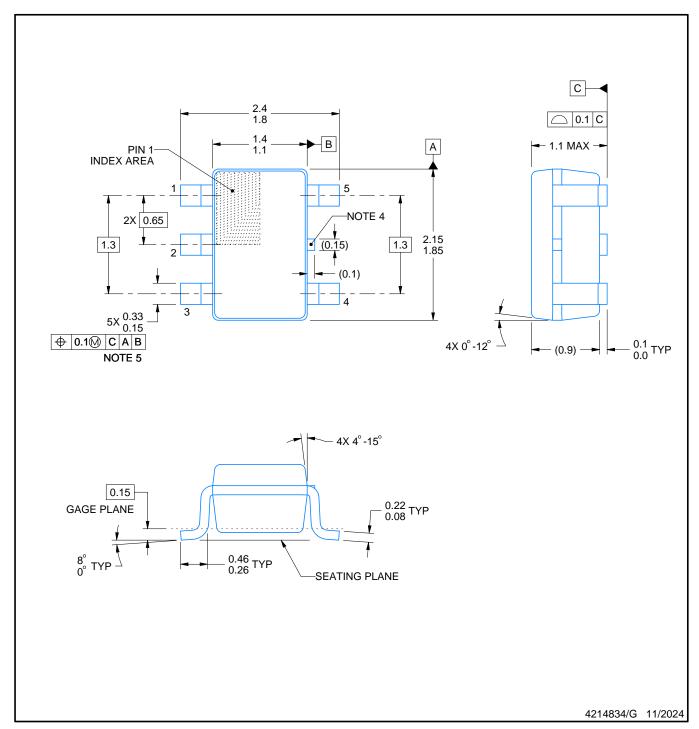
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV9001QDBVRQ1	SOT-23	DBV	5	3000	210.0	185.0	35.0
TLV9001QDCKRQ1	SC70	DCK	5	3000	190.0	190.0	30.0
TLV9002QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
TLV9002QDRQ1	SOIC	D	8	2500	356.0	356.0	35.0
TLV9004QDRQ1	SOIC	D	14	2500	356.0	356.0	35.0
TLV9004QDYYRQ1	SOT-23-THIN	DYY	14	3000	336.6	336.6	31.8
TLV9004QPWRQ1	TSSOP	PW	14	3000	356.0	356.0	35.0

DCK0005A

SOT - 1.1 max height

SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Refernce JEDEC MO-203.

- 4. Support pin may differ or may not be present.
- 5. Lead width does not comply with JEDEC.
- 6. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25mm per side



SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 7. Publication IPC-7351 may have alternate designs.
- 8. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

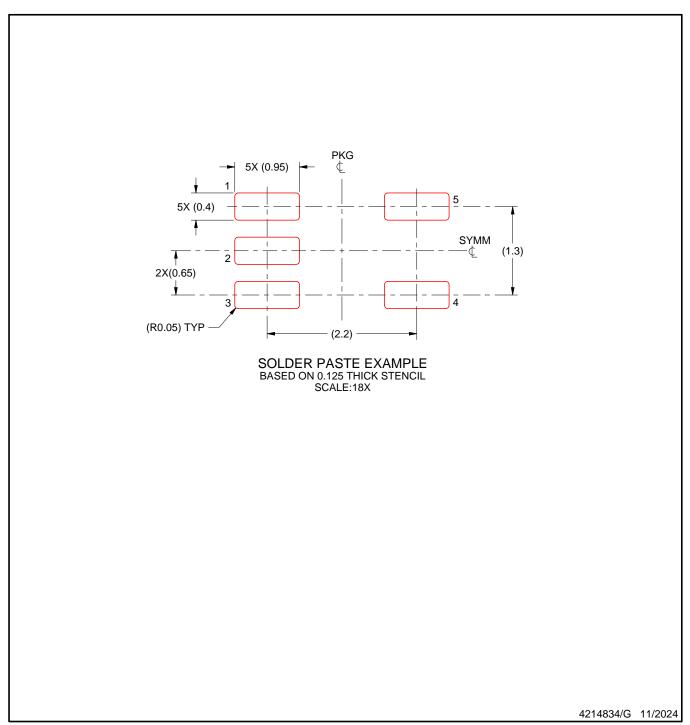


EXAMPLE STENCIL DESIGN

DCK0005A

SOT - 1.1 max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

- 9. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 10. Board assembly site may have different recommendations for stencil design.

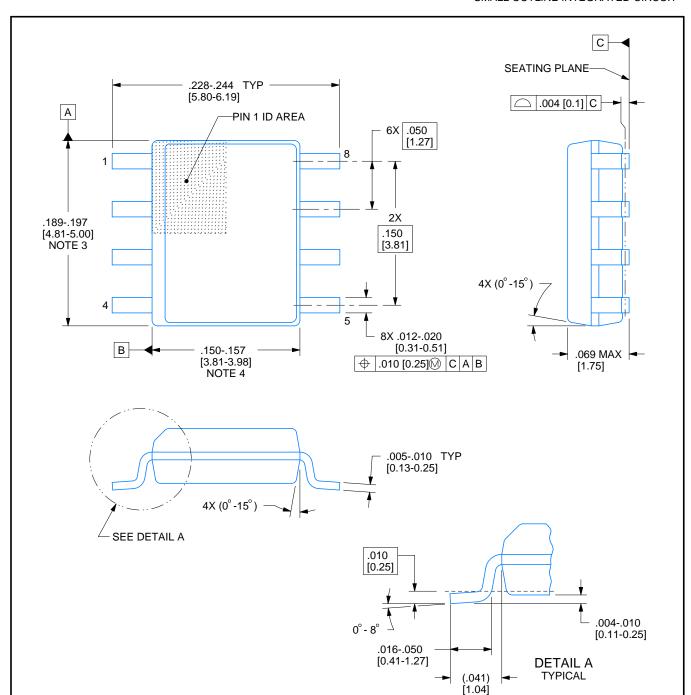


PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

4214825/C 02/2019

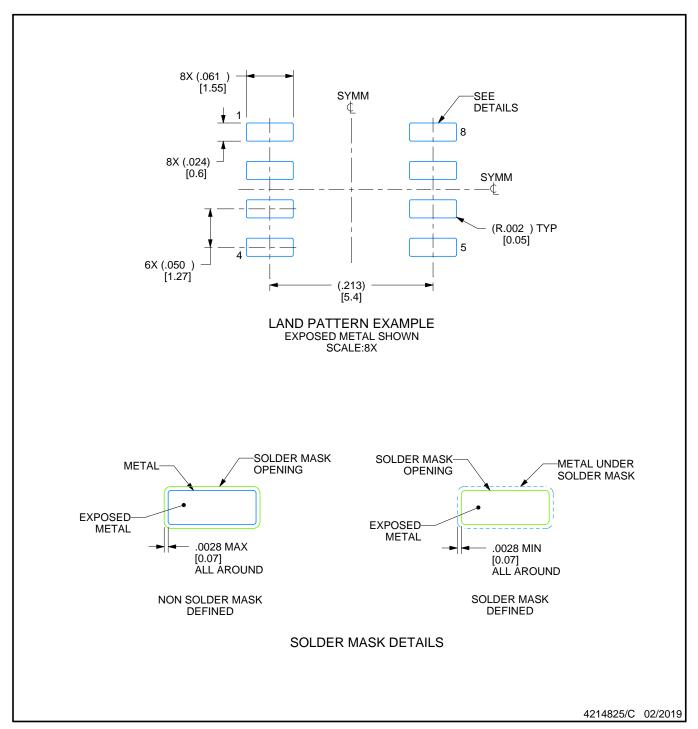


NOTES:

D0008A

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





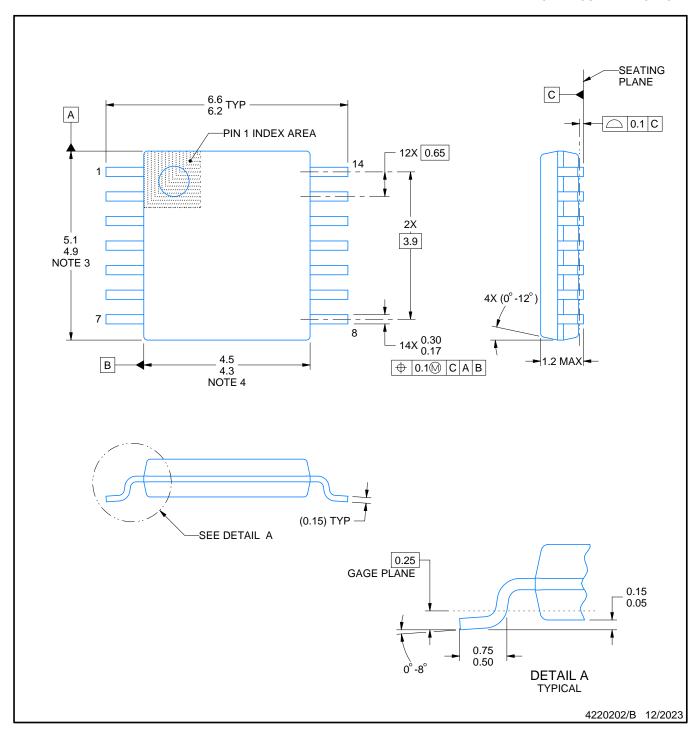
- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

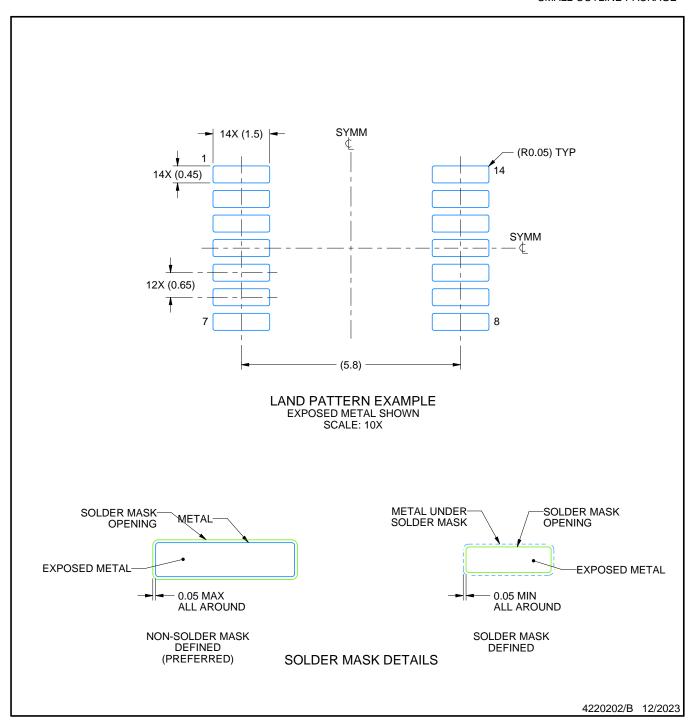
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



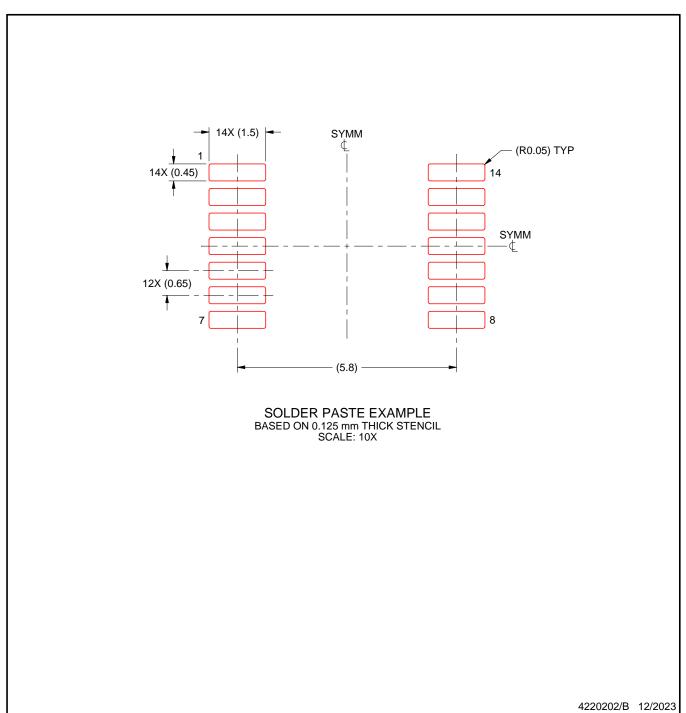
SMALL OUTLINE PACKAGE



- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



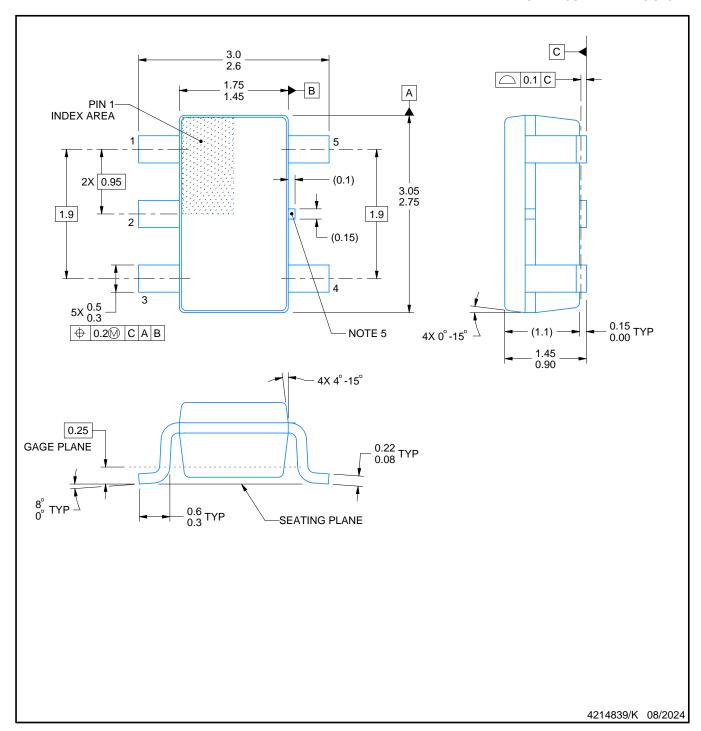
- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES:

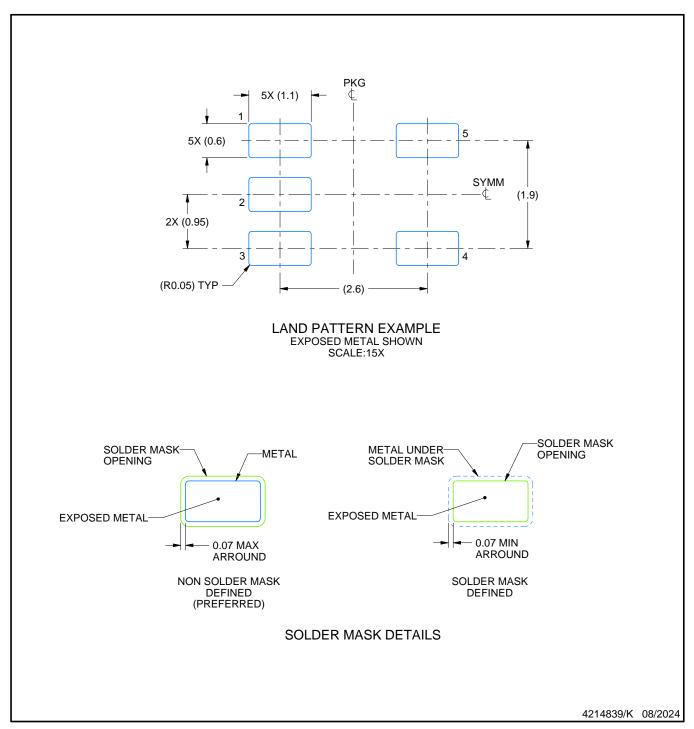
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 2. This drawing is subject to change without notice.
 3. Refernce JEDEC MO-178.

DBV0005A

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.
- 5. Support pin may differ or may not be present.



SMALL OUTLINE TRANSISTOR



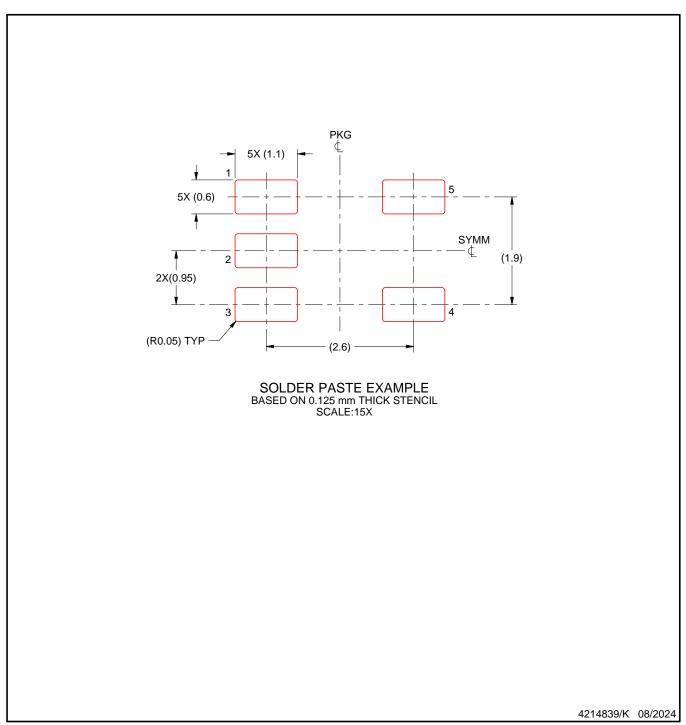
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE TRANSISTOR



- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.

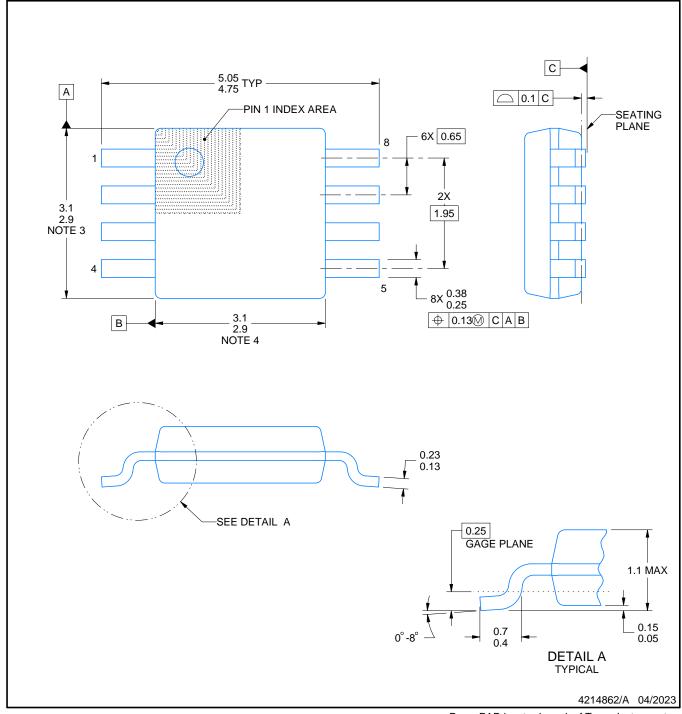


PACKAGE OUTLINE

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE





NOTES:

PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-187.



EXAMPLE BOARD LAYOUT

DGK0008A

[™] VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
- 9. Size of metal pad may vary due to creepage requirement.



EXAMPLE STENCIL DESIGN

DGK0008A

™ VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE

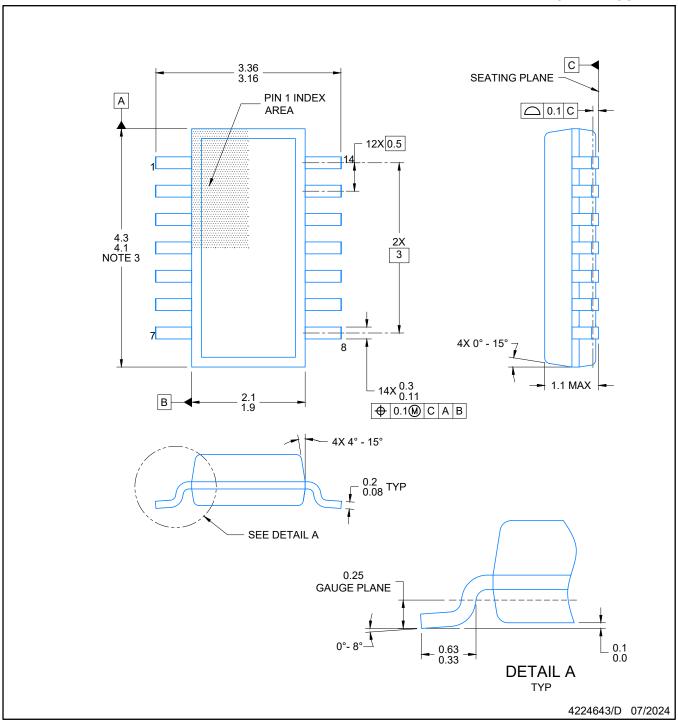


- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.



SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



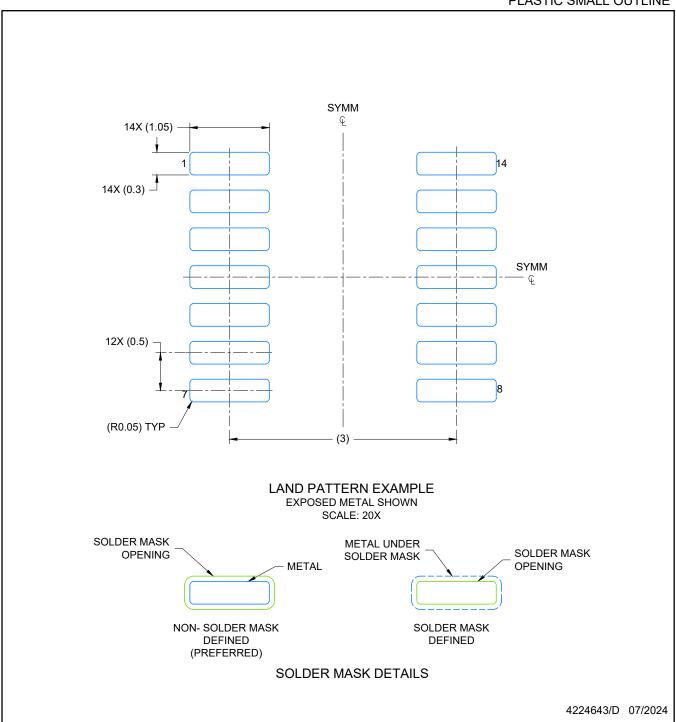
NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per side
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- 5. Reference JEDEC Registration MO-345, Variation AB



SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE

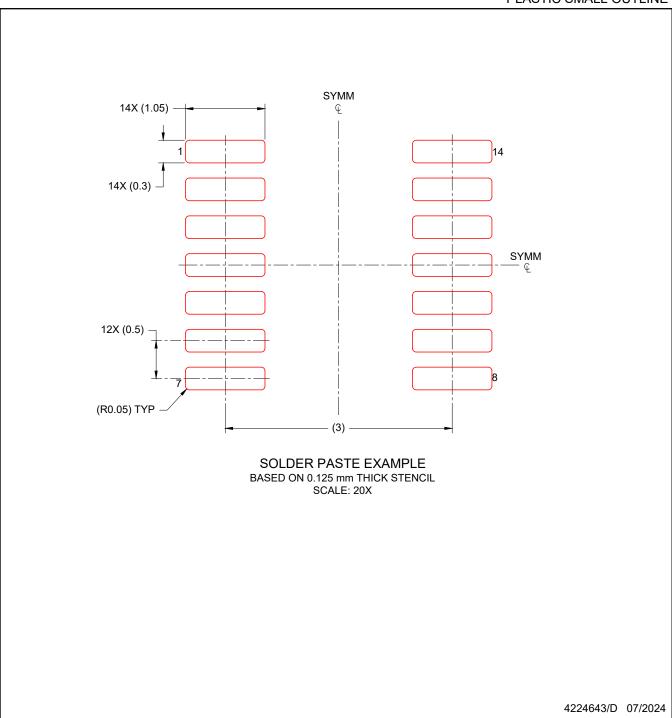


- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.

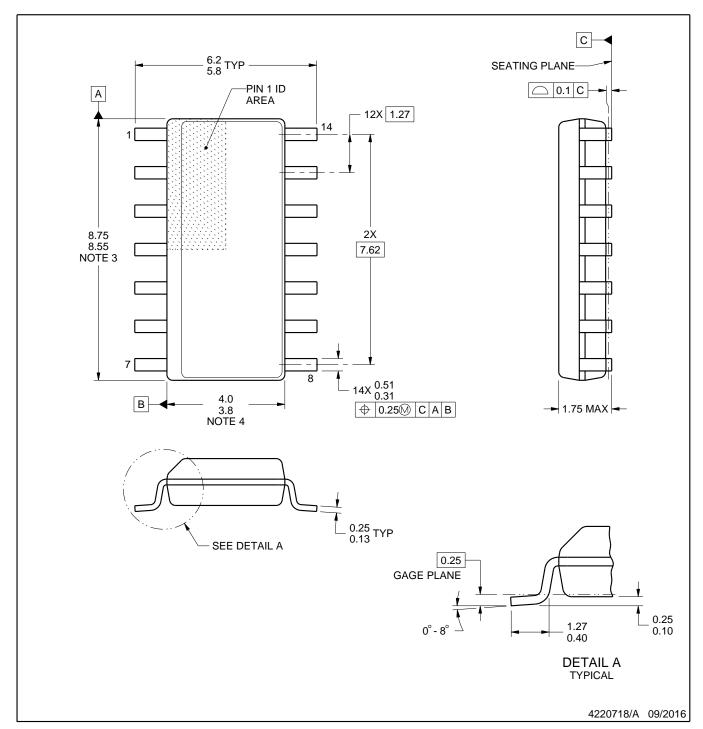




SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

PACKAGE OUTLINE



NOTES:

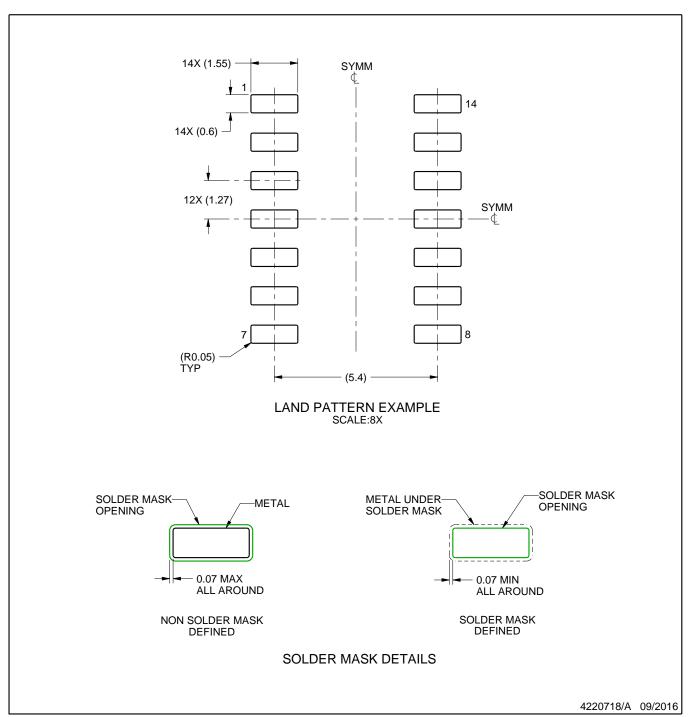
D0014A

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.





- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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